Application/Control No.	Applicant(s)/Patent under Reexamination	
10/659,307	TANAKA ET AL.	
Examiner	Art Unit	
Cong-Lac Huynh	2178	

SEARCHED				
Class	Subclass	Date	Examiner	
715	500	5/18/2007	CLH	
	500.1	6/1/2007	CLH	
	722	6/1/2007	CLH	
	723	6/1/2007	CLH	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE EXM		
East	6/1/2007 CLH		
ACM	6/1/2007 CLH		